PD-97593B

International **tor** Rectifier

Radiation Hardended Ultra Low DropoutIRUH330133BPFixed Positive Linear Regulator+5.0VIN to +3.3VOUT @3.0A

Product Summary

Part Number	Dropout	۱ ₀	V _{IN}	V _{OUT}
IRUH330133BK	0.4V	2.04	5.01/	2.21/
IRUH330133BP	0.4V	3.0A	5.0V	3.3V



(5962F1023505K)

IRUH330133BK IRUH330133BP

Description

The IRUH330133 is a space qualified, ultra low dropout linear regulator designed specifically for applications requiring high reliability, low noise and radiation hardness.

Features

- Silicon On Insulator (SOI) CMOS Regulator IC, CMOS Latch-Up Immune, Inherently Rad Hard
- Total Dose Capability up to 300Krads(Si) (Condition A); Tested to 500Krad (Si)
- ELDRS up to 100Krad(Si) (Condition D)
- SEU Immune up to LET = 80 MeV*cm²/mg
- Space Level Screened
- Fast Transient Response
- Timed Latch-Off Over-Current Protection
- Internal Thermal Protection
- On/Off Control via Shutdown Pin, Power Sequencing Easily Implemented
- Isolated Hermetic MO-078 Package Ensures Higher Reliability
- This part is also available in 8-Lead Flat Pack Package as IRUH330133AK / IRUH330133AP

Absolute Maximum Ratings

Parameter	Symbol	Min.	Max.	Units	
Power Dissipation @ T _C = 125°C	PD	-	25	W	
Maximum Output Current @ Maximum			See Fig 4	А	
Power Dissipation with no Derating	I _O	-	See Fig 4	A	
Non-Operating Input Voltage	V _{IN}	-0.3	+8.0		
Operating Input Voltage	V _{IN}	2.9	6.4		
Ground	GND	-0.3	0.3	V	
Shutdown Pin Voltage	V _{SHDN}	-0.3	V _{IN} + 0.3	1	
Output Pin Voltage	V _{OUT}	-0.3	V _{IN} + 0.3		
Operating Case Temperature Range	Τ _Ο	-55	+140		
Storage Temperature Range	Τ _S	-65	+150	°C	
Maximmum Junction Temperature	ТJ	-	+150		
Lead Temperature (Soldering 10sec)	ΤL	-	+300	1	
Pass Transistor Thermal Resistance, Junction to Case	R _{THJC}	-	1.0	°C/W	

Electrical Characteristics ① **Pre-Radiation** @T_c = 25°C, V_{IN} = 5.0V (Unless Otherwise Specified)

Parameter	Test Conditions	Symbol	Min.	Тур.	Max.	Units
Output Voltage ①	$3.8V \leq V_{IN} \leq 5.8V, \ 50mA \ \leq I_{OUT} \leq 3.0A$		3.250	3.3	3.349	
	$3.8V \leq V_{IN} \leq 5.8V, \ 50mA \ \leq I_{OUT} \leq 3.0A,$		3.201	3.3	3.399	V
	-55°C to +125°C	V _{OUT}	3.201	3.3	3.399	
	$3.8V \leq V_{IN} \leq 5.8V, \ 50mA \ \leq I_{OUT} \leq 3.0A,$		3.184	3.3	3.366	
	Post -Rad		5.104	0.0	5.500	
Dropout Voltage ①	$I_{O} = 3.0A, V_{OUT} = 3.3V, -55^{\circ}C \text{ to } +125^{\circ}C,$	V	_	-	0.4	V
	Post -Rad	V _{DROP}				
Current Limit	Over-Current Latching, -55°C to +125°C,	ILATCH	3.5	-	-	А
	Post -Rad	LATCH	0.0			
Over-Current Time-to-Latch	I _O > I _{LATCH}	t _{LATCH}	-	10	-	ms
Maximum Shutdown Temp. [®]		T _{LATCH}	125	140	-	°C
Ripple Rejection [®]	F= 120Hz, I _O = 50mA, -55°C to +125°C	PSRR	65	-	-	dB
	F= 120Hz, I _O = 50mA, Post -Rad	FONN	40	-	-	
V _{SENSE} Pin Current ^②	-55°C to +125°C	ISENSE	-	1.6	-	mA
Minimum SHDN Pin "On"	I _{SOURCE} = 200μA, -55°C to +125°C	V	-	-	0.8	V
Threshold Voltage	Post -Rad	V _{SHDN}				
Maximum SHDN Pin "Off"	I _{SOURCE} = 200μA, -55°C to +125°C	W	1.2	-	-	V
Threshold Voltage	Post -Rad	V _{SHDN}	1.2			
Output Voltage at Shutdown	R _{LOAD} = 36 Ohms, V _{SHDN} = 5.0V	V	-0.1	-	0.1	V
	-55°C to +125°C, Post-Rad	V _{OUT}				
SHDN Pin Leakage Current ^②	V _{SHDN} = 3.3V, -55°C to +125°C,Post-Rad	I _{SHDN}	-10	-	10	μA
SHDN Pin Pull-Up Current [®]	$V_{SHDN} = 0.4V$	I _{SHDN}	-98	-	-56	μΑ
	V _{SHDN} = 0.4V, -55°C to +125°C		-140	-	-30	
	V _{SHDN} = 0.4V, Post-Rad		-98	-	-56	
Power On Reset Threshold ©	Sweep V _{IN} and Measure Output	V _{T-POR}	-	1.7	-	V
Quiescent Current @	No Load	la	-	-	15	mA
	Full Load	ΙQ	-	-	90	

Notes:

0 Connected as shown in Fig.1 and measured at the junction of V_{OUT} and V_{SENSE} Pins. 0 Under normal closed-loop operation. Guaranteed by design. Not tested in production.

Radiation Performance Characteristics

Test	Conditions	Min	Тур	Unit
	MIL-STD-883, Method 1019 (Condition A)			
Total Ionizing Dose (Gamma)	Operating Bias applied during exposure	300	500 O	Krads (Si)
	Minimum Rated Load, Vin = 6.4V			
	MIL-STD-883, Method 1019 (Condition D)			
Total Ionizing Dose (Gamma)	(ELDRS) Operating Bias applied during	100	See ②	Krads (Si)
	exposure Minimum Rated Load, Vin = 6.4V			
Single Event effects	Heavy lons (LET)			
SEU, SEL, SEGR, SEB	Operating Bias applied during exposure	84		MeV*cm ² /mg
	under varying operating conditions			
Neutron Fluence	MIL-STD-883, Method 1017		1.0e ¹¹	Neutrons/cm ²

Notes:

Tested to 500Krad (Si).
See Fig. 5.

Space Level Screening Requirements

TEST/INSPECTION	SCREENING LEVEL	MIL-STD-883		
	SPACE	METHOD		
Nondestructive Bond Pull	100%	2023		
Internal Visual	100%	2017		
Seal	100%	1014		
Temperature Cycle	100%	1010		
Constant Acceleration	100%	2001		
Mechanical Shock	100%	2002		
PIND	100%	2020		
Pre Burn-In-Electrical	100%			
Burn-In	100%	1015		
Final Electrical	100%			
Radiographic	100%	2012		
External Visual	100%	2009		

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Application Information

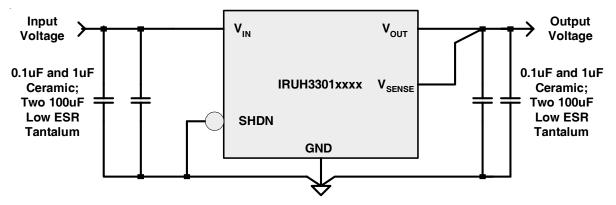


Fig. 1. Typical Regulator Circuit; Note the SHDN Pin is hardwired in the "ON" position. The V_{SENSE} Pin is connected as noted in the "General Layout Rules" section.

Over-Current & Over-Temperature Protection

The IRUH3301 series provides over-current protection by means of a timed latch function. Drive current to the internal PNP pass transistor is limited by an internal resistor (Rb in Fig. 3) between the base of the transistor and the control IC drive FET. If an over-current condition forces the voltage across this resistor to exceed 0.5V (nom), the latch feature will be triggered. The time-to-latch (t_{LATCH}) is nominally 10ms. If the over-current condition exists for less than t_{LATCH} , the latch will not be set. If the latch is set the drive current to the PNP pass transistor will be disabled. The latch will remain set until one of the following actions occur:

- 1. The SHDN Pin voltage is brought above 1.2V and then lowered below 0.8V.
- 2. The V_{IN} Pin voltage is lowered below 1.7V.

If the junction temperature of the regulator IC exceeds 140°C nominal, the thermal shutdown circuit will set the internal latch and disable the drive current to the PNP pass transistor as described above. After the junction temperature falls below a nominal 125°C, the latch can be reset using either of the actions described above.

Under-Voltage Lock-Out

The under-voltage lock-out (UVLO) function prevents operation when V_{IN} is less than 1.7V (nominal). There is a nominal 100mV hysteresis about this point.

Input Voltage Range

The device control functions fully when V_{IN} is greater than 2.8V. The device enters into undervoltage lock-out when V_{IN} < 1.7V (nominal). When 1.7V (nominal) < V_{IN} < 3.7V, V_{OUT} will track V_{IN} and overshoot may occur. A larger output capacitor should be used to slow down the V_{OUT} rise rate for slow V_{IN} ramp applications.

Shutdown (SHDN)

The regulator can be shutdown by applying a voltage of >1.2V to the SHDN Pin. The regulator will restart when the SHDN Pin is pulled below the shutdown threshold of 0.8V. If the remote shutdown feature is not required, the SHDN Pin should be connected to GND.

Input Capacitance

Input bypass capacitors: Two $(0.1\mu$ F and 1μ F) ceramics and two 100μ F low ESR tantalums (AVX TPS or equivalent), placed very close to the V_{IN} Pin are required for proper operation. When the input voltage supply capacitance is more than 4 inches from the device, additional input capacitance is recommended. Larger input capacitor values will improve ripple rejection further improving the integrity of the output voltage.

Output Capacitance

Output bypass capacitors: Two $(0.1\mu$ F and 1μ F) ceramics and two 100μ F low ESR tantalums (AVX TPS or equivalent) are required for loop stability. Faster transient performance can be achieved with multiple additional 1μ F ceramic capacitors. Ceramic capacitors greater than 1μ F in value are not recommended as they can cause stability issues.

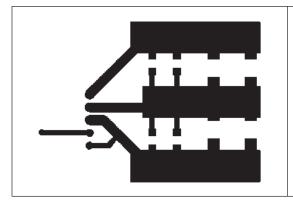
Tantalum capacitor values larger than the suggested value are recommended to improve the transient response under large load current changes. The upper capacitance value limit is governed by the delayed over-current latch function of the regulator and can be as much as $10,000\mu$ F without causing the device to latch-off during start-up.

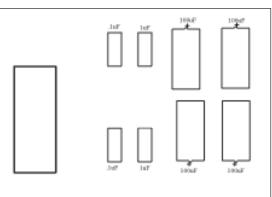
General Layout Rules

Low impedance connections between the regulator output and load are essential. Solid power and ground planes are highly recommended. In those cases where the board impedances are not kept very small, oscillations can occur due to the effect of parasitic series resistance and inductance on loop bandwidth and phase margin.

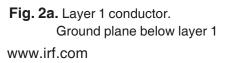
The V_{SENSE} Pin must be connected directly to the V_{OUT} Pin using as short a trace as possible with the connection inside the first bypass capacitor (see Fig. 2a).

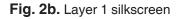
Connect ceramic output capacitors directly across the V_{OUT} and GND Pins with as wide a trace as design rules allow (see Fig. 2a). Avoid the use of vias for these capacitors and avoid loops. Fig.2 shows the ceramic capacitors tied directly to the regulator output.





The input capacitors should be connected as close a possible to the $\rm V_{_{\rm IN}}$ Pin.





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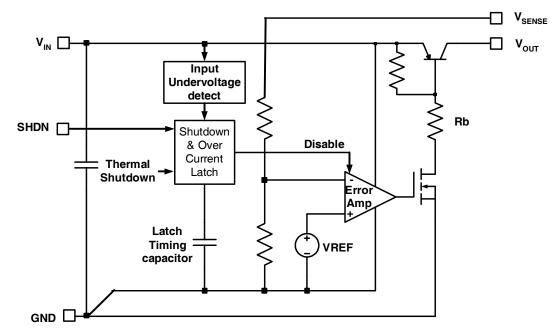


Fig. 3. Simplified Schematic Circuit

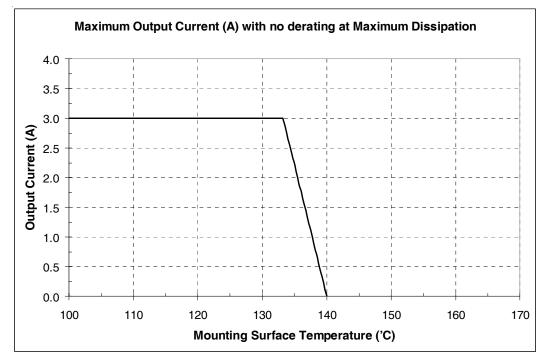


Fig. 4. Maximum Output Current versus Mounting Surface Temperature with no Derating at Maximum Dissipation

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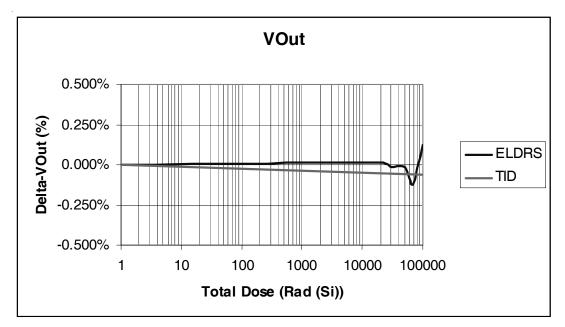


Fig. 5. Change in Output Voltage vs. Total Ionizing Dose Radiation Exposure at Both High and Low Dose Rates

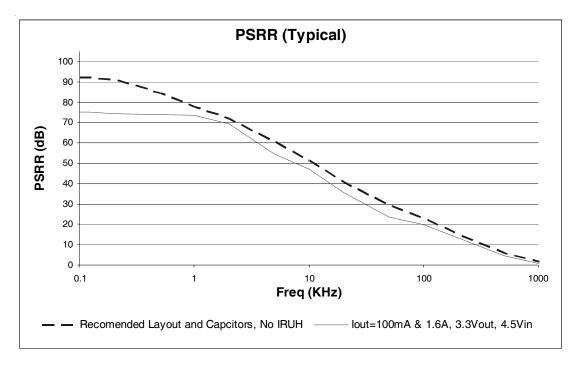


Fig. 6. Typical Power Supply Ripple Rejection at 100mA and 1.6A using recommended layout and capacitors. Results above 10KHz are influenced by testing setup and layout.

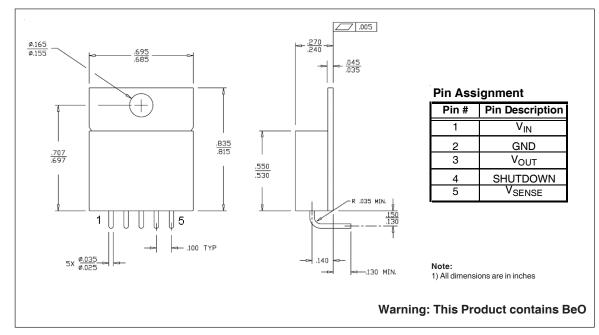
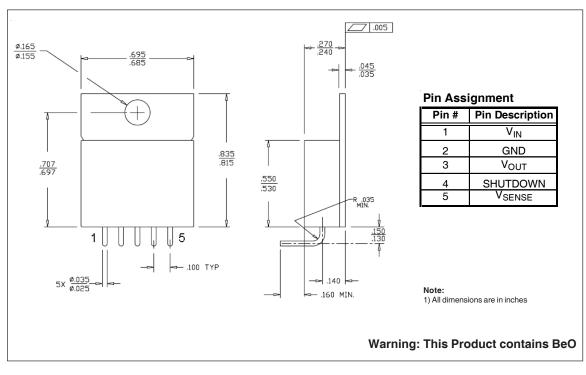


Fig 7. Case Outline and Dimensions - MO-078AA (Lead Form Down)





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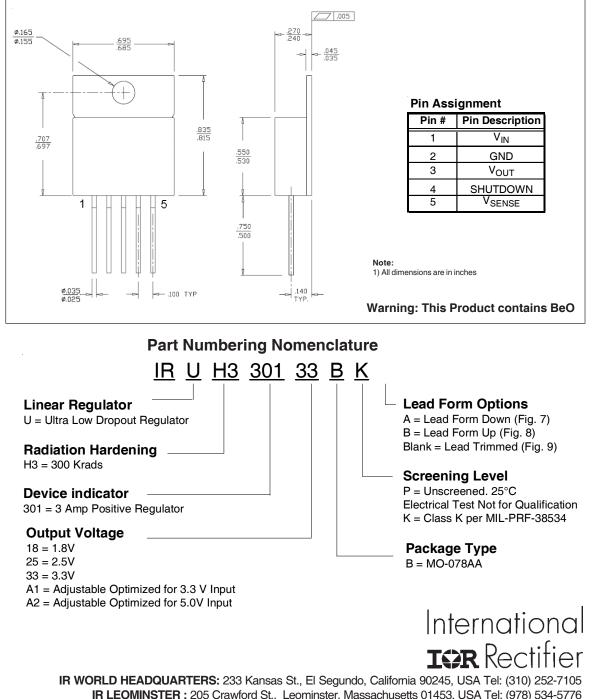


Fig 9. Case Outline and Dimensions - MO-078AA (Lead Trimmed)

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Data and specifications subject to change without notice. 05/2012